

SHEET 1 OF 1

Form PTO 1449  
(Modified)U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICEATTY DOCKET NO.  
220302US0SERIAL NO.  
10/091,402

## LIST OF REFERENCES CITED BY APPLICANT

APPLICANT

Hajime ITOH, et al.

FILING DATE

March 7, 2002

GROUP

2879

## U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
OK	AA	4,919,700	04/24/90	G. A. PECORARO, et al.			
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
	AM						
	AN						

## FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO
	AO				
	AP				
	AQ				
	AR				
	AS				
	AT				
	AU				
	AV				

## OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

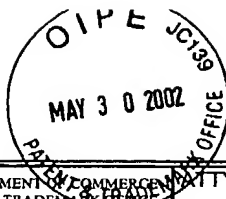
	AW	C. TANAKA, et al., Proceedings of the International Conference on Science and Technology of New Glasses, No. A4, XP-002141801, pps. 71-76, "REFINING OF GLASSES UNDER SUBATMOSPHERIC PRESSURES", October 16, 1991
	AX	
	AY	
	AZ	

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## U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
ML	AA	6,332,339	12/25/2001	T. KAWAGUCHI, et al.			
CL	AB	6,294,005	09/25/2001	S. INOUE, et al.			
CL	AC	6,251,811	06/26/2001	O. YANAGISAWA, et al.			
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## FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION	
					YES	NO
	AO	2000-128549	05/09/2000	JAPAN (with English Abstract)		X
	AP	2000-239023	09/05/2000	JAPAN (with English Abstract)		X
	AQ					
	AR					
	AS					
	AT					
	AU					
	AV					

## OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

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